

Notice of References Cited	Application/Control No. 10/600,450	Applicant(s)/Patent Under Reexamination OTAKE, YUKIO	
	Examiner Thai-Ba Trieu	Art Unit 3748	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-4,054,112	10-1977	Kurokawa et al.	123/383
	B	US-6,652,233 B2	11-2003	Otake, Yukio	416/30
	C	US-6,171,055 B1	01-2001	Vos et al.	416/30
	D	US-4,626,170	12-1986	Dorsch, Heinz	416/30
	E	US-4,864,993	09-1989	Itoh et al.	123/383
	F	US-4,512,307	04-1985	Igashira et al.	123/383
	G	US-2,818,847	01-1958	MOCK FRANK C	416/29
	H	US-3,913,542	10-1975	Uitti et al.	60/611
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 08200117 A	08-1996	Japan	FUJIMURA, ITSUKI	F02D 41/02
	O	JP 2000289494 A	10-2000	Japan	KOBAYASHI et al.	F02D 23/00
	P	JP 07189747 A	07-1995	Japan	MINAMI, MINORU	F02D 01/02
	Q	JP 04081528 A	03-1992	Japan	FUJIMURA, ITSUKI	F02D 01/02
	R	JP 07109938 A	04-1995	Japan	YABE et al.	F02D 41/02
	S	JP 09088667 A	03-1997	Japan	TANAKA et al.	F02D 41/04
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.